

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination BEHEL ET AL.	
		Examiner Hai L. Nguyen	Art Unit 2816	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
X	A	US-6,711,395	03-2004	Tonegawa et al.	455/313
X	B	US-6,696,888	02-2004	Gilbert, Barrie	327/560
X	C	US-6,690,236	02-2004	Saito, Shinji	330/254
X	D	US-6,657,494	12-2003	Twomey, Gerald J.	330/254
X	E	US-6,591,093	07-2003	Coffing et al.	455/319
X	F	US-6,591,091	07-2003	Vorenkamp et al.	455/179.1
X	G	US-6,590,438	07-2003	Manku et al.	327/359
X	H	US-6,564,043	05-2003	Rauhala, Antti Heikki Tapani	455/251.1
X	I	US-6,563,374	05-2003	Jaussi et al.	327/562
X	J	US-6,510,314	01-2003	Kuo, Yao Hsien	455/326
X	K	US-6,118,339	09-2000	Gentzler et al.	330/149
X	L	US-5,815,039	09-1998	Kimura, Katsuji	330/252
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	V	
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	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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